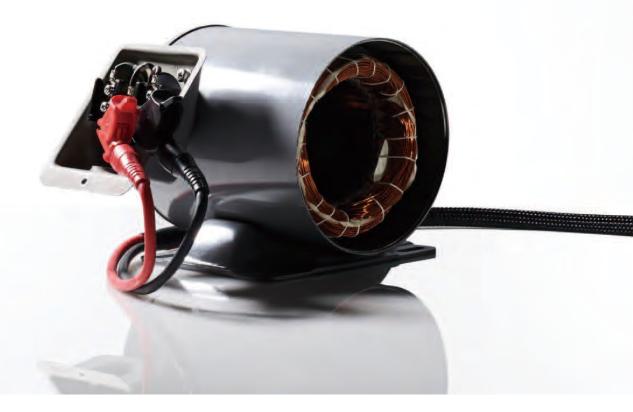


NEW



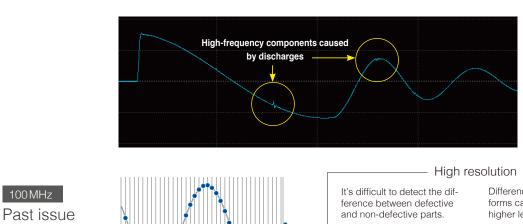
The new standard in winding testing

Detect defects that were impossible to detect in the past



Detect minuscule changes in response waveforms

High-speed sampling × high resolution



200 MHz
ST4030A
Instantaneous variations

Difficult to detect instantaneous variations

It's difficult to detect the difference between defective and non-defective parts.

Differences between waveforms can be captured at a higher level of detail.

10 bit

12 bit

Response waveform

Response waveform

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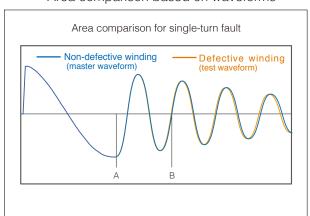
Detect single-turn faults

Quantification of response waveforms

Conventional approach

NEW

Area comparison based on waveforms

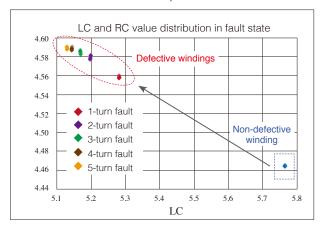


Pass/fail judgments are difficult when area differences do not exceed several percentage points.

Pass/fail judgments are made by calculating the difference in area between the master waveform and the test waveform for the interval specified by the A and B cursors.

New approach

Quantification of response waveforms



The distributions of values differ for defective and non-defective windings.

The new approach of using LC and RC values makes it possible to detect discrepancies between defective and non-defective windings, including when the differences between waveforms are too minuscule to detect using conventional means*. Since detection thresholds can be clearly defined, the instrument can give provide a clear pass/fail decision.

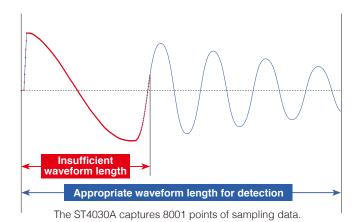
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Ample sampling data for proper detection

Capture minuscule variations in response waveforms

However, since the ST4030A supports a large number of sampling points, the instrument can capture waveforms of sufficient length to support detection, even when sampling at 200 MHz.





Improved applied voltage reproducibility

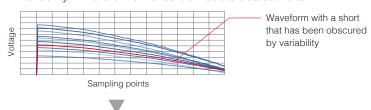
Detect defective parts with a high degree of repeatability

The ST4030A can detect defective parts with a high degree of precision thanks to low variability in the applied voltage it generates. In addition, differences between instruments when testing the same workpiece are slight, so you can continue to use master workpiece data even after one instrument is swapped out for another.

Applied voltage variability

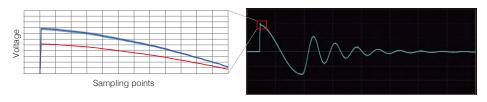
Conventional instruments

Variability in waveforms makes it difficult to detect shorts.



ST4030A

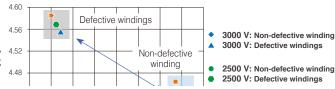
Low waveform variability allows defective windings to be detected with a high degree of precision.



Reduced damage thanks to lower applied voltages

LC and RC values can be used to distinguish between defective and non-defective parts, without regard to the magnitude of the applied voltage. As a result, the applied voltage can be lowered, reducing damage to workpieces.

The distributions of values differ even when the applied voltage is reduced, allowing the instrument to distinguish between defective and non-defective windings.



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RC Lu

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Optional upgrade for the ST4030A

NEW

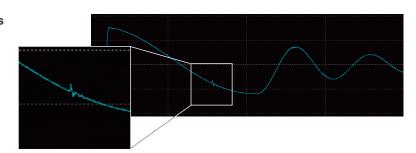
DISCHARGE DETECTION UPGRADE ST9000

Detect pseudo-shorts with a high degree of precision

By detecting minuscule partial discharges that are obscured by noise, the ST9000 makes it possible to detect insulation defects (pseudo-shorts) between motor windings.

Proprietary Hioki filtering process

Of the high-frequency components that appear in response waveforms, noise components that appear throughout the waveform are rejected so that the instrument can extract and make judgments based solely on partial discharge components.



High-precision waveform detection

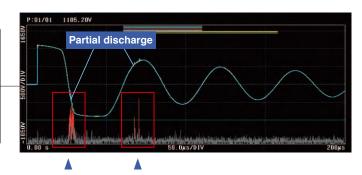
200 MHz, 12-bit sampling

Isolation of noise components

Proprietary HIOKI filter

Easy discharge detection

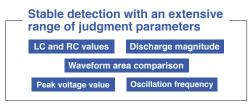
No need for peripheral equipment (discharge detection antenna, etc.)



High-frequency discharge components are isolated by a proprietary Hioki filtering process.

Insulation breakdown voltage testing (Break Down Voltage)

The ST4030A also provides functionality for performing insulation breakdown voltage testing, which is required by various standards. An impulse test is performed while the voltage applied to the workpiece is gradually increased, and the insulation breakdown voltage is evaluated based on factors such as the response waveform's LC and RC values, the amount of discharge, and the waveform area.

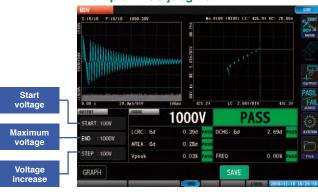


BDV setting range

Setting range: 100 V to 4200 V

Setting resolution: 10 V Number of steps: Up to 32

Example PASS judgment



Example FAIL judgment (discharge FAIL at 2000 V)



Testing after rotor assembly

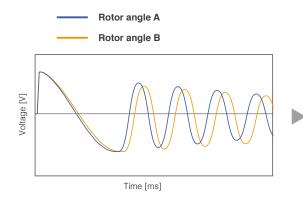


Conventional waveform detection

Clear judgment standards cannot be defined due to differences in the response waveforms depending on the position and angle at which the rotor has been attached.

Variations in the voltage waveform when the rotor is rotated (simplified illustration)

Since the waveform varies depending on the locations at which rotor angles A and B occur, it is difficult to determine a standard to use to compare the waveforms.

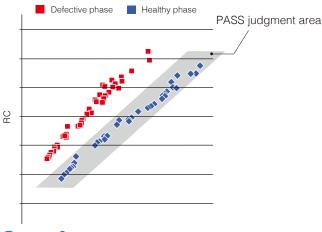


Numerical judgment using LC and RC values

If the non-defective part area is set using healthy phases, impulse testing can be performed following rotor assembly.

Distribution of LC and RC values when the rotor is rotated (at 50 points)

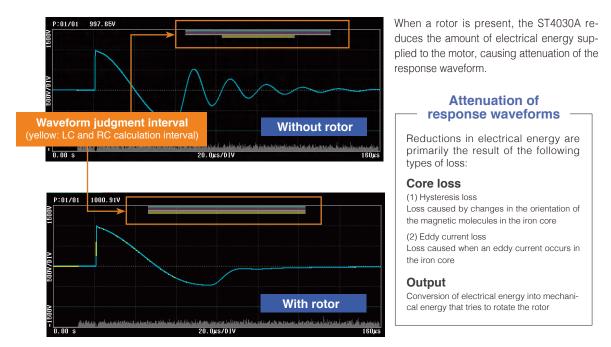
When LC and RC values are sampled while rotating the rotor, the distribution for defective phases differs from the distribution for healthy phases.



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Accommodating differences in response waveform caused by motor characteristics

When testing a motor whose response waveform exhibits reduced resonance due to rotor core loss, the ST4030A automatically adjusts the judgment interval so that evaluations can be made over an interval with high voltage amplitude.

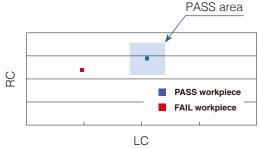


As long as the response waveforms for defective and non-defective motors differ, even if they are attenuated, the motors can be tested.

Improve parts quality by using quantified test results as feedback for upstream processes Quantitatively manage testing by quantifying response waveforms

Clarify judgment standard values

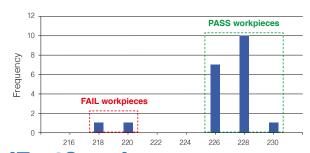
Clearly determine judgment standards based on numerical data for defective and non-defective workpieces. This information provides a basis for understanding how much the two can differ.



Use test results to manage manufacturing quality

Utilize statistical quality control techniques and accumulate statistical data to estimate when winding defects will occur so as to properly take steps to prevent such issues.

Workpiece	LC[p]	RC [μ]
1	228	4.21
2	227	4.22
3	226	4.22
4	228	4.23
5	227	4.22
6	226	4.21
7	227	4.23
8	225	4.22
	219	6.51
17	227	4.22



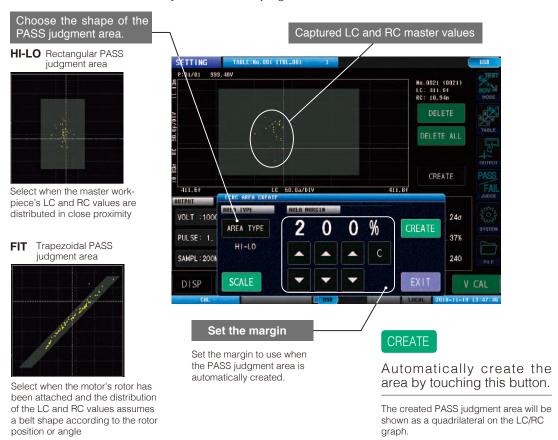
Create a PASS judgment area from the distribution of LC and RC values

Full support to assist in setting testing conditions

Automatic configuration of the PASS judgment area

To make PASS and FAIL judgments, capture master LC and RC values from a known-good master workpiece.

The ST4030A will automatically create a PASS judgment area based on those values.



Automatic configuration of the waveform capture range

The oscillation frequency of response waveforms varies with the type of workpiece. To allow a sufficient amount of waveform data to be used in LC/RC value calculation and waveform judgment, the sampling frequency and sampling data count are automatically adjusted so as to optimize the waveform capture range.

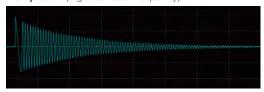
Workpiece A (low oscillation frequency)



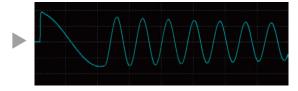
The captured waveform length is inadequate due to the response waveform's low oscillation frequency. The sampling frequency needs to be decreased.

Optimizing the waveform capture range

Workpiece B (high oscillation frequency)



Waveform length after optimization using automatic adjustment



An unnoceeery amount of waveforms is being contured

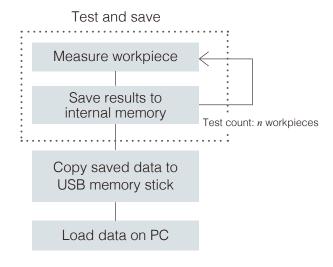
Functionality for recording and utilizing quantified test results

Easily analyze test results on a computer

Memory function and USB memory stick



The ST4030A can save the results of up to 1000 tests in its internal memory. You can then copy that data to a USB memory stick, open the measurement data using a spreadsheet application, and use it to analyze variability and manage testing data.



Data stored in internal memory

Test results: CSV file format

Data that can be saved to a USB memory stick

Test results: CSV file format Measurement screens: BMP file Instrument settings: User-defined table settings and all other settings

Analyze data using a spreadsheet application

Support for PLC and computer programming

Build testing lines quickly

EXT. I/O test

Verify whether signals output from the external control terminal (EXT. I/O) are being properly output and whether input signals are being properly read.

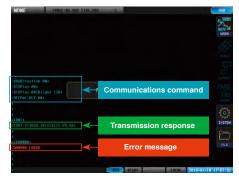


I/O OUT: The signal is output (turned on) from the I/O output pin with the name of the selected button.

I/O IN: The names of signals being input (turned on) are shown in green Signals

Communications monitor

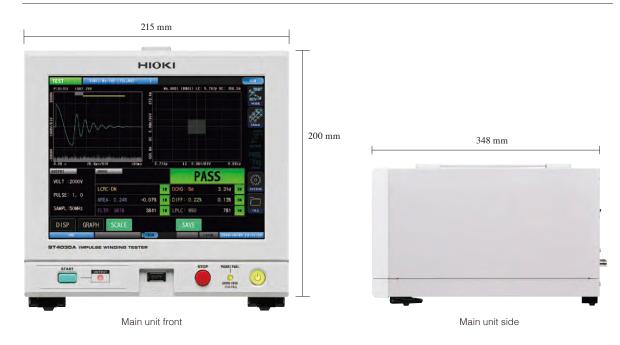
Since you can display communications and query responses on the screen, you can build a testing line while checking the status of instrument operation in real time.

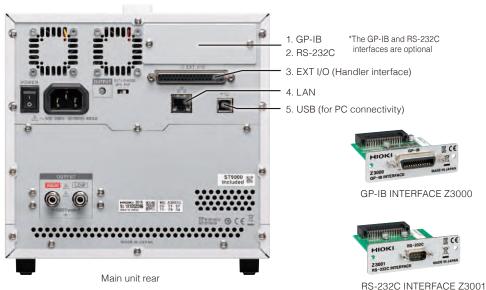


Commands are shown on the communications monitor in different colors to simplify the process of verifying proper operation.

Ideal for embedding in winding inspection systems

Space-saving Half-rack Size





Extensive range of interfaces

Interfaces

The ST4030A can be controlled from a computer using communications commands sent via its USB, LAN, GP-IB, or RS-232C interface.

LAN

Connector	RJ-45 connector
Connector	113-43 CONNECTOR
Electrical specifications	IEEE802.3 compliant
Transmission method	10BASE-T/ 100BASE-TX/ 1000BASE-T Auto detected
Protocol	TCP/IP

GP-IB (optional)

Reference standard	IEEE-488.2		
Functional specifications	SH1 AH1 T6 L4 SB1 BL1 PP0 DC1 DT1 C0		

USB (for PC connectivity)

Connector	ur USB Type B receptacle	
Electrical specifications	USB2.0 (Full Speed/High Speed)	

RS-232C (optional)

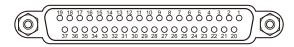
Connector	D-sub 9-pin male connector	
Communication method	Full duplex	
Synchronization method	Start stop synchronization	

EXT. I/O

The EXT. I/O interface allows you to output signals such as the measurement complete signal (EOM) and the judgment results signal (PASS/FAIL) to an external device and to control the instrument based on input such as a START signal from an external device.

Connectors

	D- sub 37-pin		
Connectors to use (unit side)	Female connector with #4-40 inch screws		
	DC-37P-ULR (solder type)		
Compliant connectors	DCSP-JB37PR (pressure weld type)		
	Japan Aviation Electronics Industry, Ltd.		



Input signals

Pin	Pin name	Description
1	START	The instrument starts testing at the START signal's ON edge.
20	STOP	The instrument stops testing when it detects the ON edge of the STOP signal during testing.
3 INTERLOCK		If the instrument's interlock setting is enabled, the interlock state is canceled while the INTER-LOCK signal is ON.
4 to 7, 22 to 25	TBL0 to 7	Selects the table number in which switchable test conditions have been saved.

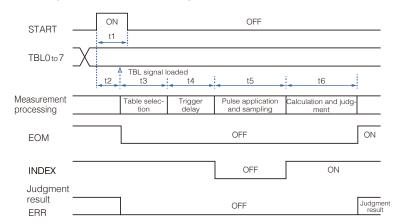
Output signals

Output	Output signals				
Pin	Pin name	Description			
29	INDEX	Indicates that analog measurement (pulse application and sampling) has ended. When this signal changes from OFF to ON, the probes can be placed in the open state.			
28	EOM	This signal is output when testing is complete. The judgment results and ERR signals are refreshed once the EOM signal is output.			
10	ERR	This signal is output when a measurement error such as an open error or hardware error occurs.			
18	PASS	This signal is output when the overall judgment result is PASS.			
37	FAIL	This signal is output when the overall judgment result is FAIL.			
11 to 13 30 to 32	OUT_XXX	These signals are output when a judgment function generates an OUT judgment.			
16, 17,35	OUT0 to 2	These signals can be used as general-purpose output. The output signal can be controlled using the :IO:OUTPut command.			

Insulated power source output

Pin	Pin name	NPN/PNP switch settings			
		NPN	PNP		
8	ISO_5V	Insulated power source +5 V	Insulated power source -5 V		
9, 27	ISO_COM	Insulated power source common	Insulated power source common		

Example of measurement timing



Item	Description	time	
t1	START signal ON time	1 ms or greater	
t2	Trigger detection time	1 ms (typical value)	
		10ms (typical value)	
t3	Table selection time	*Add the internal discharge time if the test voltage for the table after switching is less than the test voltage before switching.	
t4	Trigger delay time	0.000s to 9.999s	
t5	Analog measurement time	50 ms (typical value for a set voltage of 3000 V, sampling frequency of 200 MHz, and 1 pulse application)	
t6	Calculation and judgment time	15ms (typical value when the AREA, DIFF, FLUTTER, or LAPLACIAN judgment function is enabled) *When applying multiple pulses, indicates the judgment and calculation times for the final pulse.	

Test times (reference values)

	Measurement times (EOM)	s EOM = (INDEX + software processing time + judgment times × number of pulses applied *Degaussing pulses do not entail software processing time or judgment time. *When applying multiple pulses, the testing process is controlled so that each pulse application interval is not less than the minimum pulse application interval set time.						
	Analog measure- ment times	Time through cha	rging, appl	ication,	and sa	ampling end (t	ypical value)	
	(INDEX)	Set voltage	100 V	1000) V	2000 V	3000 V	
	,	INDEX time	30 ms	30 r	ns	40 ms	50 ms	
	Software processing time	g time Processing time: 10 ms *S/s: 200 MHz, DISP: THIN						
	Judgment time				d (typical value	e)		
		Judgment	Processir	ng time				
		AREA*1 1 ms						
		DIFF*1 1 ms						
FLTR*1 1 ms			s	1				
		LAPC*1	1 m	s	*1 Judgment area: 1500 pt *2 Calculation interval: 1500 pt			
		LC·RC*2 100		ns	*3 Judgment interval with sampling			speed
DISCHARGE*			75ms of 200 MHz: 8001 pt		pt			
		l						

Electrical specifications

	Input type	Photocoupler-isolated non-voltage contact input (with current sink/source output support)
Input signals	Input ON	Residual voltage of 1 V or less; input ON current of 4 mA (reference values)
	Input OFF	OPEN (breaking current of 100 μA or less)
	Output type	Photocoupler-isolated open-drain output (non-polar)
Output signals	Maximum load voltage	DC 30 V
Output signals	Maximum load current	50 mA/ch
	Residual voltage	1 V or less (load current of 50 mA) / 0.5 V or less (load current of 10 mA)
	Output voltage	Sink output support: +5.0 V ±0.8V; source output support: -5.0 V ±0.8 V
1.1. 0.2.1.1	Maximum autaut aurrant	100 m/s

Specifications (Accuracy guaranteed for 1 year, Post-adjustment accuracy guaranteed for 1 year)

Applied voltage	100 V to 4200 V (resolution set in 10 V steps)		
Testable inductance range	10 μH to 100 mH		
Sampling speed	200 MHz / 100 MHz / 50 MHz / 20 MHz /10 MHz		
Sampling resolution	12 bit		
Voltage detection accuracy	DC accuracy: ±5% of setting, AC band: 100 kHz, ±1 dB Accuracy guarantee conditions: 23°C ±5°C, 80% RH or less		
Number of samples	1001 to 8001 points (set in 1000 point steps)		
Judgment method	The same impulse voltage is applied to a master workpiece and the workpiece under test, and a PASS/FAIL judgment is made by comparing the shapes, LC and RC values, and discharge component magnitudes of the respective response waveforms.		
	LC/RC value judg- ment	LC/RC value judgment (LCRC AREA)	
	Waveform judgment	Waveform area comparison judgment (AREA) Waveform differential area comparison judgment (DIFF-AREA) Waveform flutter detection judgment (FLUTTER) Waveform second derivative detection judgment (LAPLACIAN)	
	Discharge detection (With ST9000)	Discharge detection (DISCHARGE)	
Insulation breakdown voltage testing mode	The workpiece is subjected to impulse testing while gradually raising the applied voltage to determine the voltage at which the insulation breaks down. Waveform area judgment, discharge judgment, and LC/RC value judgment are used to judge insulation breakdown.		
Number of test condition tables	255 (test condition settings, detection condition settings, master waveforms)		
Test duration	Approx. 60 ms (reference value when tester is configured for 3000 V, 1 pulse, detection off)		
Display	Touch screen display: 8.4-inch SVGA color TFT LCD (800 × 600 dots)		
Safety functionality	Key lock, interlock, double-action design (to prevent erroneous operation when starting testing)		

General specifications

*Maximum applied energy: Approx. 88 mJ

denoral opcomoditions		
Operating environment	Use indoors at an elevation of 2,000 m or less in an environment with a maximum pollution level of 2	
Operating temperature and humidity range	0°C to 40°C (32°F to 104°F), 80% RH or less (no condensation)	
Storage temperature and humidity	-10°C to 50°C (14°F to 122°F), 80% RH or less (no condensation)	
Standards compliance	Safety: EN 61010, EMC: EN 61326 Class A	
Power supply	AC100 V to 240V, 50 Hz/60 Hz	
External interface	Standard equipment: EXT. I/O, USB host (memory stick), USB device (for communications), LAN Options: RS-232C (Z3001), GP-IB (Z3000)	
Dimensions	Approx. 215 mm (8.46 in) W × 200 mm (7.87 in) H × 348 mm (13.7 in) D (excluding protrusions)	
Mass	Approx. 6.7 kg (236.3 oz)	
Accessories	Power cord, instruction manual, application disc, operating precautions	

Model: IMPULSE WINDING TESTER ST4030A

Model No. (Order Code) ST4030A

Additional function options

DISCHARGE DETECTION UPGRADE ST9000

The Discharge Detection Upgrade ST9000 is a factory option for the Impulse Winding Tester ST4030A. Please specify at the time of order.

Options





Caution: Effect of cable parasitic components

The oscillation waveform varies with the length of the cable. Please contact your Hioki distributor concerning availability of special-order cables whose capacitance values fall within the acceptable range.









Z3000

CABLE 9151-02 Z3001 2 m (6.56 ft) length

9 pin - 9 pin, cross, 1.8 m (5.91 ft) length